



NDT452P P-Channel Enhancement Mode Field Effect Transistor

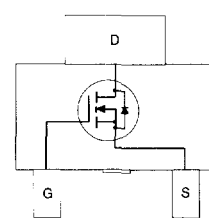
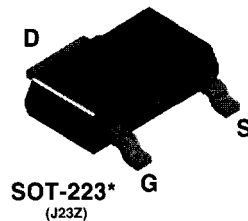
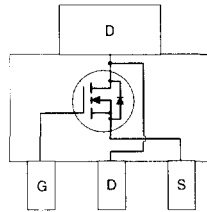
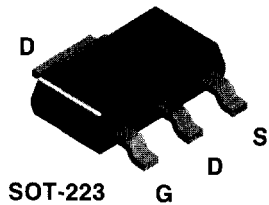
General Description

Power SOT P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance and provide superior switching performance. These devices are particularly suited for low voltage applications such as notebook computer power management and DC motor control.

Features

- -3A, -30V. $R_{DS(ON)} = 0.18\Omega @ V_{GS} = -10V$.
- High density cell design for extremely low $R_{DS(ON)}$.
- High power and current handling capability in a widely used surface mount package.

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Absolute Maximum Ratings $T_A = 25\text{ C unless otherwise noted}$

Symbol	Parameter	NDT452P	Units
V_{DSS}	Drain-Source Voltage	-30	V
V_{GSS}	Gate-Source Voltage	± 20	V
I_D	Drain Current - Continuous (Note 1a)	± 3	A
	- Pulsed	± 20	
P_D	Maximum Power Dissipation (Note 1a) (Note 1b) (Note 1c)	3	W
		1.3	
		1.1	
T_J, T_{STG}	Operating and Storage Temperature Range	-65 to 150	C

THERMAL CHARACTERISTICS

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1a)	42	C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case (Note 1)	12	C/W

* Order option J23Z for cropped center drain lead.

Electrical Characteristics (T _A = 25°C unless otherwise noted)						
Symbol	Parameter	Conditions	Min	Typ	Max	Units
OFF CHARACTERISTICS						
V _{DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = -250 μA	-30			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -24 V, V _{GS} = 0 V			-2	μA
		T _J = 55°C			-25	μA
I _{GSSF}	Gate - Body Leakage, Forward	V _{GS} = 20 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate - Body Leakage, Reverse	V _{GS} = -20 V, V _{DS} = 0 V			-100	nA
ON CHARACTERISTICS (Note 2)						
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = -250 μA	-1	-2	-3	V
		T _J = 125°C	-0.85	-1.7	-2.6	
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = -10 V, I _D = -3 A		0.15	0.18	Ω
		T _J = 125°C		0.23	0.32	
		V _{GS} = -4.5 V, I _D = -2.2 A		0.27	0.32	
I _{D(on)}	On-State Drain Current	V _{GS} = -10 V, V _{DS} = -5 V	-15			A
		V _{GS} = -4.5 V, V _{DS} = -5 V	-4.5			
g _{FS}	Forward Transconductance	V _{DS} = -15 V, I _D = -3 A		3.7		S
DYNAMIC CHARACTERISTICS						
C _{iss}	Input Capacitance	V _{DS} = -10 V, V _{GS} = 0 V, f = 1.0 MHz		525		pF
C _{oss}	Output Capacitance			300		pF
C _{rss}	Reverse Transfer Capacitance			130		pF
SWITCHING CHARACTERISTICS (Note 2)						
t _{D(on)}	Tum - On Delay Time	V _{DD} = -10 V, I _D = -1.0 A, V _{GEN} = -10 V, R _{GEN} = 6 Ω		8	40	ns
t _r	Tum - On Rise Time			15	40	ns
t _{D(off)}	Tum - Off Delay Time			25	90	ns
t _f	Tum - Off Fall Time			8	50	ns
Q _g	Total Gate Charge	V _{DS} = -10 V, I _D = -3 A, V _{GS} = -10 V		15	25	nC
Q _{gs}	Gate-Source Charge			1.6	4	nC
Q _{gd}	Gate-Drain Charge			4.5	8	nC

Electrical Characteristics ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS						
I_S	Maximum Continuous Drain-Source Diode Forward Current				-2.5	A
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0\text{ V}$, $I_S = -3\text{ A}$ (Note 2)			-1.2	V

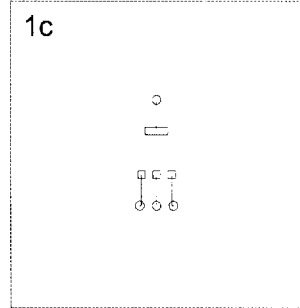
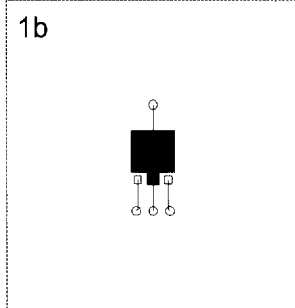
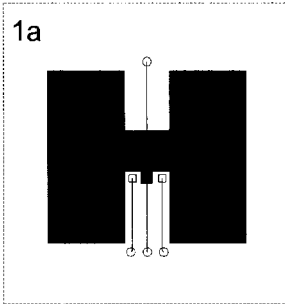
Notes:

- $R_{th,jc}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{th,jc}$ is guaranteed by design while $R_{th,ja}$ is determined by the user's board design.

$$P_D(t) = \frac{T_J - T_A}{R_{th,ja}(t)} = \frac{T_J - T_A}{R_{th,jc} + R_{th,ca}(t)} = I_D^2(t) \times R_{DS(on)}@T_J$$

Typical $R_{th,ja}$ using the board layouts shown below on 4.5"x5" FR-4 PCB in a still air environment:

- 42°C/W when mounted on a 1 in² pad of 2oz copper.
- 95°C/W when mounted on a 0.066 in² pad of 2oz copper.
- 110°C/W when mounted on a 0.0123 in² pad of 2oz copper.



Scale 1 : 1 on letter size paper

- Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2.0\%$.

Typical Electrical Characteristics

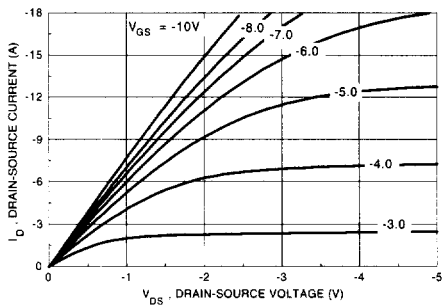


Figure 1. On-Region Characteristics.

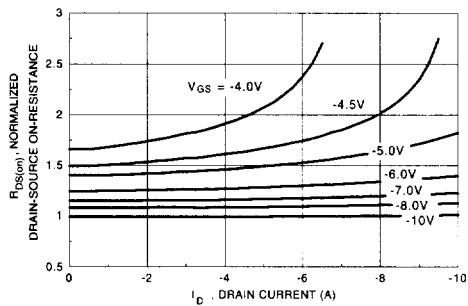


Figure 2. On-Resistance Variation with Gate Voltage and Drain Current.

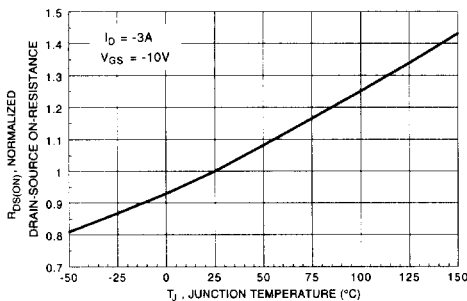


Figure 3. On-Resistance Variation with Temperature.

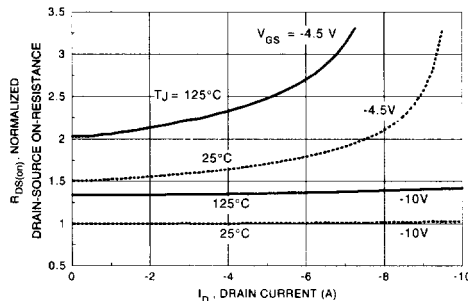


Figure 4. On-Resistance Variation with Drain Current and Temperature.

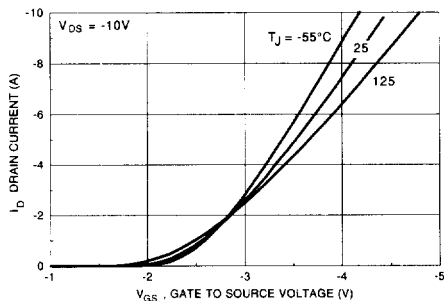


Figure 5. Transfer Characteristics.

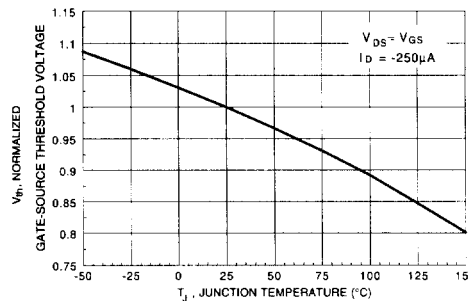


Figure 6. Gate Threshold Variation with Temperature.

Typical Electrical Characteristics (continued)

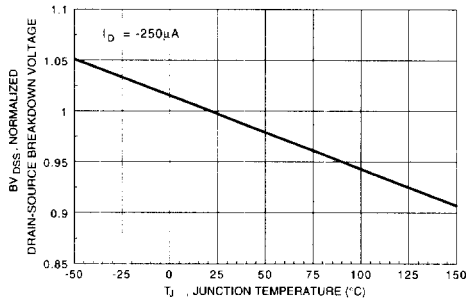


Figure 7. Breakdown Voltage Variation with Temperature.

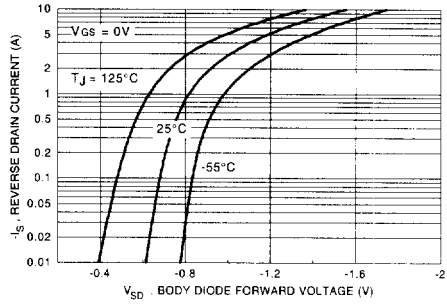


Figure 8. Body Diode Forward Voltage Variation with Current and Temperature.

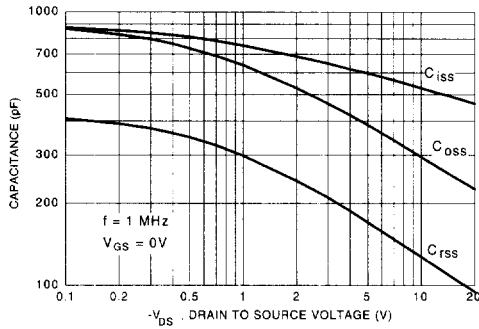


Figure 9. Capacitance Characteristics.

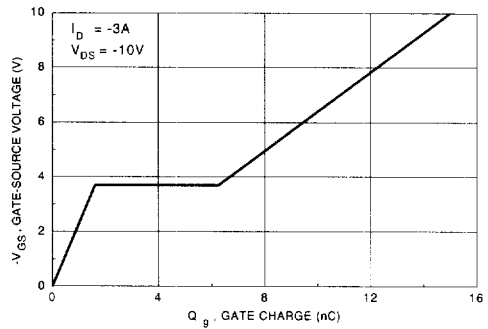


Figure 10. Gate Charge Characteristics.

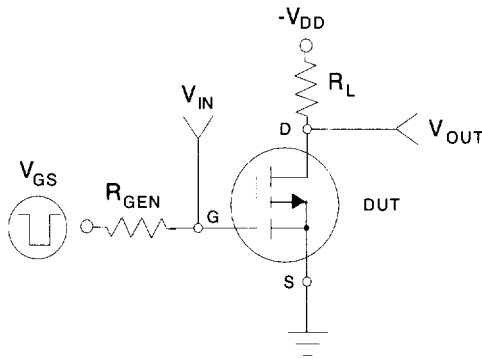


Figure 11. Switching Test Circuit.

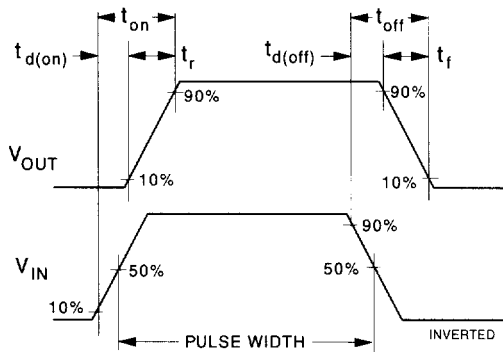


Figure 12. Switching Waveforms.

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Typical Electrical Characteristics (continued)

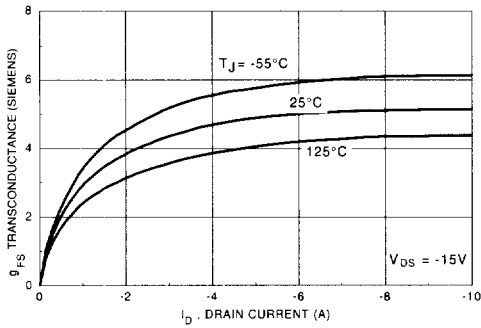


Figure 13. Transconductance Variation with Drain Current and Temperature.

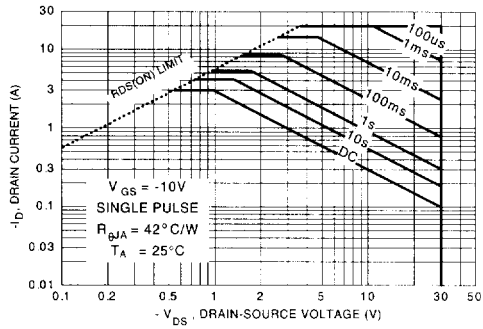


Figure 14. Maximum Safe Operating Area.

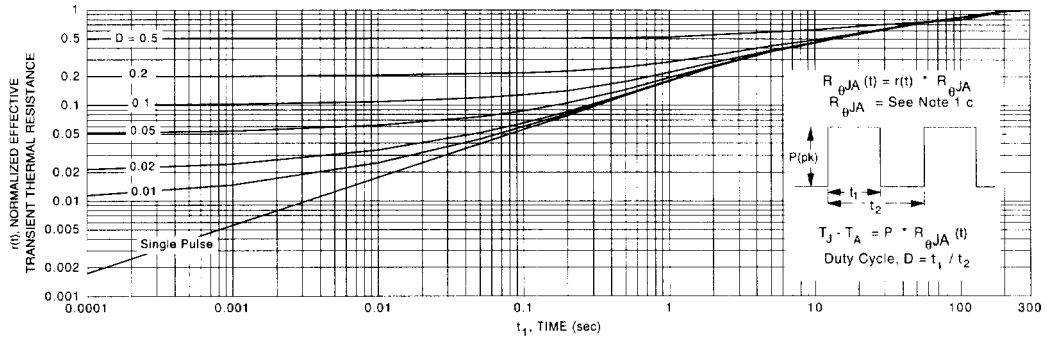


Figure 15. Transient Thermal Response Curve.

Note: Thermal characterization performed using the conditions described in note 1c. Transient thermal response will change depending on the circuit board design.